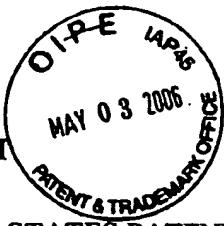


DOCKET NO: 265253US2PCT



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF : DATE ALLOWED: 02/13/06  
RYOJI SETAKA, ET AL. : EXAMINER: HOLLINGTON, J.M.  
SERIAL NO: 10/522,537 :  
FILED: JANUARY 27, 2005 : GROUP ART UNIT: 2829  
FOR: ANISOTROPIC CONDUCTIVITY :  
CONNECTOR, PROBE MEMBER,  
WAFER INSPECTING DEVICE, AND  
WAFER INSPECTING METHOD

AMENDMENT UNDER 37 CFR §1.312

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Notice of Allowance dated February 13, 2006, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.

Please enter  
J.M.H  
5/24/06